

Si9424DY

Single P-Channel 2.5V Specified PowerTrench MOSFET

General Description

This P-Channel 2.5V specified MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

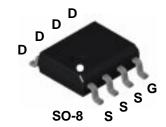
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

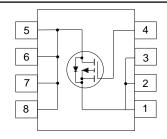
Applications

- DC/DC converter
- Load switch
- Battery Protection

Features

- -8.0 A, -20 V. $R_{DS(on)} = 0.024~\Omega~$ @ $V_{GS} =$ -4.5 V $R_{DS(on)} = 0.032~\Omega~$ @ $V_{GS} =$ -2.5 V.
- Low gate charge (23nC typical).
- Fast switching speed.
- $\bullet \;\;$ High performance trench technology for extremely low $R_{\mbox{\tiny DS(ON)}}.$
- High power and current handling capability.





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		± 10	V
I _D	Drain Current - Continuous	(Note 1a)	-8.0	Α
	- Pulsed		-50	
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
TJ, Tsta	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{ heta^{JA}}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
$R_{ heta$ JC	Thermal Resistance, Junction-to-Case	(Note 1)	25	∘C/W

Package Outlines and Ordering Information

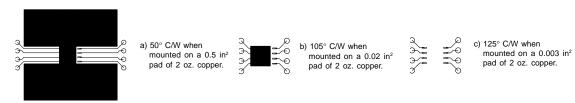
1 dokago Oddinioo ana Ordornig information					
Device Marking	Device	Reel Size	Tape Width	Quantity	
9424	Si9424DY	13"	12mm	2500 units	

©2001 Fairchild Semiconductor International Si9424DY Rev.A

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-20			V
ABVDSS	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-24		mV/∘C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 10 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -10 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-0.4	-0.8	-1.5	V
AVGS(th)	Gate Threshold Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		5		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -8 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -8 \text{ A}, T_J = 125 ^{\circ}\text{C}$ $V_{GS} = -2.5 \text{ V}, I_D = -7 \text{ A}$		0.019 0.026 0.027	0.024 0.039 0.032	Ω
I _{D(on)}	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5.0 \text{ V}$	-50			Α
G FS	Forward Transconductance	V _{DS} = -5 V, I _D = -8 A		28		S
Dvnamio	Characteristics					
Ciss	Input Capacitance	V _{DS} = -10 V, V _{GS} = 0 V,		2260		pF
Coss	Output Capacitance	f = 1.0 MHz		500		pF
C _{rss}	Reverse Transfer Capacitance			205		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, I_D = -1 \text{ A},$		8	16	ns
t _r	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		15	27	ns
t _{d(off)}	Turn-Off Delay Time			98	135	ns
t _f	Turn-Off Fall Time			35	55	ns
$\overline{Q_g}$	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -8 \text{ A},$		23	33	nC
$\overline{Q_gs}$	Gate-Source Charge	$V_{GS} = -5 V$,		5.5		nC
Q_{gd}	Gate-Drain Charge			4		nC
Drain-So	ource Diode Characteristics an	d Maximum Ratings				
I _S	Maximum Continuous Drain-Source Did				-2.1	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = -2.1 A (Note 2)		-0.75	-1.2	V

Notes

1: $R_{\theta,JA}$ is the sum of the junction-to-case and case-to-ambient resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta,JC}$ is guaranteed by design while $R_{\theta,JA}$ is determined by the user's board design.



Scale 1 : 1 on letter size paper

2: Pulse Test: Pulse Width $\leq 300~\mu s$, Duty Cycle $\leq 2.0\%$

Si9424DY Rev.A

Typical Characteristics

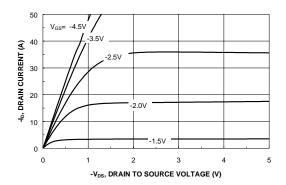


Figure 1. On-Region Characteristics.

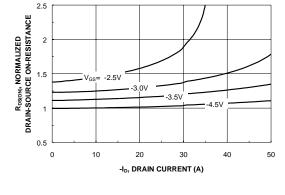


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

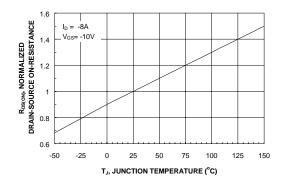


Figure 3. On-Resistance Variation with Temperature.

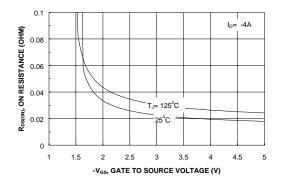


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

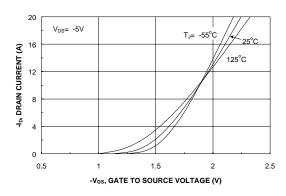


Figure 5. Transfer Characteristics.

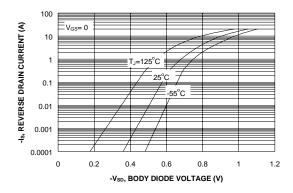
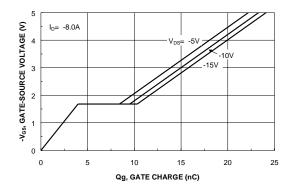


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Si9424DY Rev.A

Typical Characteristics (continued)



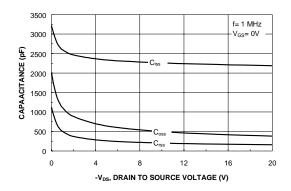
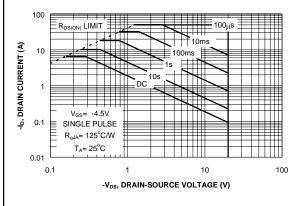


Figure 7. Gate Charge Characteristics.





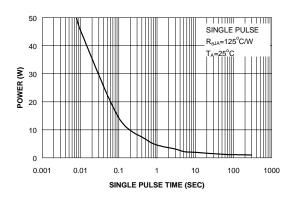


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

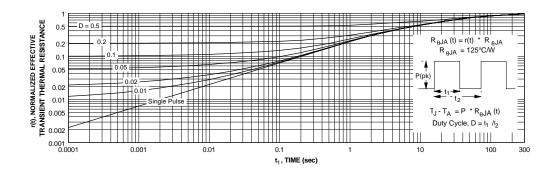


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient themal response will change depending on the circuit board design.

Si9424DY Rev.A

TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

 $ACEx^{TM}$ FASTr™ PowerTrench® SyncFET™ QFET™ TinyLogic™ Bottomless™ GlobalOptoisolator™ QSTM UHC™ CoolFET™ GTO™ **VCX**TM $CROSSVOLT^{TM}$ QT Optoelectronics™ HiSeC™

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.

2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

Rev. G